

Notice of References Cited	Application/Control No. 09/765,430	Applicant(s)/Patent Under Reexam Nagashima et al.	
	Examiner Anil Khatri	Art Unit 2122	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY ¹	Name	Classification ²	
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NON-PATENT DOCUMENTS

*		Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
x	U	Austin et al, "Efficient detection of all pointers and arrays access errors", SIGPLAN ACM, pp 290-301
x	V	Edelson, "A mark and sweep collector for C + +", ACM pp 51-58
x	W	Hayes, "Using key object opportunism to collect old objects", ACM OOPSLA, pp 33-46
x	X	Jarvinen et al, "Object oriented specification of reactive systems", IEEE, pp 63-71

* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a). ¹ Dates in MM-YYYY format are publication dates. ² Classifications may be U.S. or foreign.